



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Inventors: Blaine R. Spady; John D. Heaton
Assignee: Nanometrics Incorporated
Title: Metrology/Inspection Positioning System
Serial No.: 09/458,123 Filing Date: December 8, 1999
Examiner: Gordon Stock Group Art Unit: 2877
Docket No.: NAN035 US Confirmation No.: 8470

Santa Clara, California
May 5, 2004

Mail Stop AF
Commissioner For Patents
P.O. Box 1450
Alexandria, VA 22313-1450

RESPONSE TO OFFICE ACTION

Dear Sir:

This Response to Office Action is responsive to the February 11, 2004, Office Action, which has a statutorily shortened period for response that ends May 11, 2004. Please consider the following arguments before taking action on the merits of the above-referenced application.

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